

**Search Notes**

Application No.

09/990,948

Examiner

Victor V Yevsikov

Applicant(s)

WU ET AL.

Art Unit

2825

**SEARCHED**

Class	Subclass	Date	Examiner
438	634,624 638,637 738,783	1/13/2005	VY
438	694,695	1/13/2005	VY
438	697,699	1/13/2005	VY
438	656,780	1/13/2005	VY

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
As above		1/13/2005	VY

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
(chemical mechanical polishing) or CMP) and (first adj conduct adj layer) with (dielectric adj layer) with substrate	1/13/2005	VY